

**Search Notes**

Application/Control No.

10/725,378

Examiner

Peter Coughlan

Applicant(s)/Patent under  
Reexamination

FAN ET AL.

Art Unit

2129

**SEARCHED**

Class	Subclass	Date	Examiner
435	184	1/19/2007	PDC
435	325	1/19/2007	PDC
435	183	1/19/2007	PDC
706	25	1/19/2007	PDC
706	16	1/19/2007	PDC
706	20	1/19/2007	PDC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East-inductive learning, learning model, feature vector, aggregate benefit, application, purpose, function, fan wei	1/19/2007	PDC
East--II--Wang haixun, yu philip s, database, segment, subset, accuracy, predicated, time, cost stepwise, progressive,	1/19/2007	PDC
IEEE--Wang haixun, yu philip s, database, segment, subset, accuracy, predicated, time, cost stepwise, progressive,	1/19/2007	PDC
IEEE--II--nductive learning, learning model, feature vector, aggregae benefit, application, purpose, function, fan wei	1/19/2007	PDC
Google-inductive learning, learning model, feature vector, aggregae benefit, application, purpose, function, fan wei	1/19/2007	PDC
Dogpile--Wang haixun, yu philip s, database, segment, subset, accuracy, predicated, time, cost stepwise, progressive,	1/19/2007	PDC
Inventors--Wang Haixun, Yu Philip S, Fan Wei	1/19/2007	PDC